

Special Issue

EUV and X-ray Wavefront Sensing

Message from the Guest Editors

The aim of this Special Issue is to collect the most recent works of world-recognized researchers, active in the study, development, calibration, and characterization of EUV (extreme ultraviolet) and X-ray wavefront sensors or wavefront techniques that are applied in at-wavelength metrology, aimed to achieve the highest accuracy and, thus, the lowest uncertainty. We cordially invite you to share your work, expertise, and insights with the dimensional measurement and calibration community, in the form of research articles and reviews.

Guest Editors

Dr. Mourad Idir

Dr. Daniele Cocco

Dr. Lei Huang

Deadline for manuscript submissions

closed (31 October 2021)



Sensors

an Open Access Journal
by MDPI

Impact Factor 3.5
CiteScore 8.2
Indexed in PubMed



mdpi.com/si/30448

Sensors
Editorial Office
MDPI, Grosspeteranlage 5
4052 Basel, Switzerland
Tel: +41 61 683 77 34
sensors@mdpi.com

[mdpi.com/journal/
sensors](https://mdpi.com/journal/sensors)





Sensors

an Open Access Journal
by MDPI

Impact Factor 3.5
CiteScore 8.2
Indexed in PubMed



[mdpi.com/journal/
sensors](https://mdpi.com/journal/sensors)



About the Journal

Message from the Editor-in-Chief

Sensors is a leading journal devoted to fast publication of the latest achievements of technological developments and scientific research in the huge area of physical, chemical and biochemical sensors, including remote sensing and sensor networks. Both experimental and theoretical papers are published, including all aspects of sensor design, technology, proof of concept and application. Sensors organizes Special Issues devoted to specific sensing areas and applications each year.

Editor-in-Chief

Prof. Dr. Vittorio M. N. Passaro

Dipartimento di Ingegneria Elettrica e dell'Informazione (Department of Electrical and Information Engineering), Politecnico di Bari, Via Edoardo Orabona n. 4, 70125 Bari, Italy

Author Benefits

Open Access:

free for readers, with article processing charges (APC) paid by authors or their institutions.

High Visibility:

indexed within Scopus, SCIE (Web of Science), PubMed, MEDLINE, PMC, Ei Compendex, Inspec, Astrophysics Data System, and other databases.

Journal Rank:

JCR - Q2 (Instruments and Instrumentation) / CiteScore - Q1 (Instrumentation)